

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/P	RUCESS CF	IANGE NO	TCE (PCN)	
PCN #: A-0603-02 DA	TE: 21-Mar-2006	MEANS OF DISTIN	IGUISHING CHANGED DEVIC	ES:
Product Affected: VFQFP-N packages (See attached affected) Date Effective: 19-Jun-2006	part # list)	□ Product Mark■ Back Mark□ Date Code□ Other	Lot # will have: "M" prefix for Carsem-Malaysia "N" prefix for Carsem-China	ι
Contact: Geoffrey Cortes				
Title: Product Quality Assurance		Attachment:	Yes No	
Phone #: (408) 284-8321				
Fax #: (408) 284-1450		Samples: Please co	ontact your local sales representati	ve for
E-mail: <u>Geoffrey.Cortes@idt.com</u>		sample re	equest & availability.	
DESCRIPTION AND PURPOSE OF CHA	ANGE:			
□ Die Technology □ Wafer Fabrication Process □ Assembly Process □ Equipment □ Material □ Manufacturing Site □ Data Sheet □ Die Technology □ This notification is to advise our customers that IDT has qualified □ CARSEM-Malaysia and CARSEM-China as alternate assembly facilities for VFQFP-N standard and green packages. There is no change to the moisture performance of the package as a result of this change. □ Please see attached for the qualification data and affected part number list. □ Other				
RELIABILITY/QUALIFICATION SUM	MARY:			
There is no expected change to the product of		erformance.		
CUSTOMER ACKNOWLEDGMENT OF IDT records indicate that you require written to grant approval or request additional inform it will be assumed that this change is accepted IDT reserves the right to ship either version on the earlier version has been depleted.	n notification of this c mation. If IDT does nable.	ot receive acknowled	gement within 30 days of this notice	
Customer:	🗆	Approval for s	shipments prior to effective	date.
Name/Date:	E-N	Mail Address:	_	
Title:	Pho	one# /Fax# :		
CUSTOMER COMMENTS:				
IDT ACKNOWLEDGMENT OF RECEI	PT:			
RECD. BY:		DATE:		

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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT I - PCN # : A-0603-02

PCN Type: Manufacturing Site - Alternate Assembly Location

Data Sheet Change: None

No change in moisture sensitivity level (MSL)

Detail Of Change:

This notification is to advise our customers that IDT has qualified CARSEM-Malaysia and CARSEM-China as alternate assembly facilities for VFQFP-N standard and green packages using assembly material set as listed in Table 1.

There is no change in the moisture sensitivity level (MSL) as a result of this change.

Attachment I outlines the qualification data Attachment II shows the affected part number list

Table 1

Description	Existing	Add	
Assembly Location	ASAT-Hong Kong, ASAT-China	CARSEM-Malaysia, CARSEM-China	
Assembly Material	Ablestik 2200 (DA), HA6 1.0mil Au (Wire), EME-G770 (MC), Copper leadframe, Sn/Pb plating (standard package) and matte 100% Sn plating (green package)	QMI519 (DA), GMG-S 1.0mil Au (Wire), EME-G770 (MC), Copper leadframe, Sn/Pb plating (standard package) and matte 100% Sn plating (green package)	

Sample Availability:

Samples are already available for customer evaluations, but may not be available for all affected devices.

Please contact your local IDT sales representative for your sample request and availability.



PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT I - PCN # : A-0603-02

A) CARSEM-Malaysia

Qualification Test Results:

Test Vehicles: 56L 8x8 mm VFQFP-N (total of 3 assembly lots)

Test Description	Test Method	Sample Size /# of Fails	Test Results (SS/Rej)
* Temperature Cycling (Cond C, 1000 cycles)	JESD22-A104-B	45/0	45/0
* Autoclave (121°C, Saturated Steam, 168 hours)	JESD22-A102-C	45/0	45/0
High Temperature Stabilization Bake (150 °C, 1000 hours)	JESD22-A103-C	77/0	77/0

Notes: * Test requires moisture pre-conditioning sequence per JESD22-A113C.

Test Vehicles: 56L 8x8 mm VFQFP-N (total of 3 assembly lots)

Test Description	Test Method	Sample Size /# of Fails	Test Results (SS/Rej)
Moisture Sensitivity Classification, L3	J-STD-020B	90/0	90/0
Internal Visual Inspection	MIL-STD-883, M2010	5/0	5/0
External Visual Inspection	JESD22-B101	25/0	25/0
X-ray Examination	MIL-STD-883, M2015	45/0	25/0
Bond Pull Test	MIL-STD-883, M2011	5/0	5/0
Resistance To Solvents	JESD22-B107C	3/0	3/0
Solderability Test	JESD22-B102D	5/0	5/0
Bake & Ball Shear Strength	JESD22-B116	5/0	5/0
Physical Dimensions	JESD22-B100-B	5/0	5/0
Die Shear Strength	MIL-STD-883, M2019	5/0	5/0

Tin Whisker Evaluation Test Results Test Vehicles: 48L 7x7 mm VFQFP-N

Test Description	Test Condition	Test Duration	Spec Limits	Test Results (SS/Rej)
Storage Test	25°C/30% - 80% RH	0, 1000, 2000 hours	40μm max.	9/0
Aging	60°C / 90% RH	0, 1000, 2000 hours	40μm max.	9/0
Temperature Cycling	-55°C to +85°C	0, 500 cycles	40μm max.	9/0



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B) CARSEM-China

Qualification Test Results:

Test Vehicles: 48L 7x7 mm VFQFP-N (total of 3 assembly lots)

Test Description	Test Method	Sample Size /# of Fails	Test Results (SS/Rej)
* Temperature Cycling (Cond C, 1000 cycles)	JESD22-A104-B	45/0	45/0
* Autoclave (121°C, Saturated Steam, 168 hours)	JESD22-A102-C	45/0	45/0
High Temperature Stabilization Bake (150 °C, 1000 hours)	JESD22-A103-C	77/0	77/0

Notes: * Test requires moisture pre-conditioning sequence per JESD22-A113C.

Test Vehicles: 48L 7x7 mm VFQFP-N (total of 3 assembly lots)

Test Description	Test Method	Sample Size /# of Fails	Test Results (SS/Rej)
Moisture Sensitivity Classification, L3	J-STD-020B	90/0	90/0
Internal Visual Inspection	MIL-STD-883, M2010	5/0	5/0
External Visual Inspection	JESD22-B101	25/0	25/0
X-ray Examination	MIL-STD-883, M2015	45/0	25/0
Bond Pull Test	MIL-STD-883, M2011	5/0	5/0
Resistance To Solvents	JESD22-B107C	3/0	3/0
Solderability Test	JESD22-B102D	5/0	5/0
Bake & Ball Shear Strength	JESD22-B116	5/0	5/0
Physical Dimensions	JESD22-B100-B	5/0	5/0
Die Shear Strength	MIL-STD-883, M2019	5/0	5/0

Tin Whisker Evaluation Test Results Test Vehicles: 48L 7x7 mm VFQFP-N

Test Description	Test Condition	Test Duration	Spec Limits	Test Results (SS/Rej)
Storage Test	25°C/30% - 80% RH	0, 1000, 2000 hours	40μm max.	9/0
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ATTACHMENT II - PCN #: A-0603-02

Affected Part Number

IDT Part Number	IDT Part Number	IDT Part Number	IDT Part Number
IDT5T2010NLGI	IDT5T93GL06NLI	IDT5T9890NLGI	IDTCSPT857CNLG
IDT5T2010NLI	IDT5T93GL10NLGI	IDT5T9890NLI	IDTCSPT857DNLG
IDT5T2110NLGI	IDT5T93GL10NLI	IDT5T9891NLGI	IDTCSPU877ANLG
IDT5T2110NLI	IDT5T93GL16NLGI	IDT5T9891NLI	IDTCSPU877DNLG
IDT5T929-10NLGI	IDT5T93GL16NLI	IDT5V2305NRI	IDTCV145NLG
IDT5T929-10NLI	IDT5T940-10NLGI	IDT5V2310NRI	IDTCV150NLG
IDT5T929-30NLGI	IDT5T940-10NLI	IDT5V9885KNLGI	IDTCV153NLG
IDT5T929-30NLI	IDT5T940-30NLI	IDT5V9885NLGI	IDTCV155NLG
IDT5T9306NLI	IDT5T9820NLGI	IDT74SSTV16859NLG	IDTCV164NLG
IDT5T9310NLI	IDT5T9820NLI	IDT74SSTVF16859NLG	IDTCV168NLG
IDT5T9316NLI	IDT5T9821NLGI	IDT74SSTVN16859CNLG	IDTCV169NLG
IDT5T93GL06NLGI	IDT5T9821NLI	IDT74SSTVN16859NLG	IDTCV171NLG